

제22회 한국반도체학술대회

2015년 2월 10일(화) - 12일(목), 인천 송도컨벤시아

H. Display and Imaging Technologies 분과

Room B
1F / 105호

2015년 2월 12일(목) 13:10-14:40

[TB2-H] Display and Imaging Technologies

좌장: 구본원 (삼성전자)

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| TB2-H-1 | 13:10-13:25 | The Capacitor-Less LED Lamp using FR-4 PCB
Woong-Hee Sim, Nam-Jin Kim, Hyun-Soo Yoon, Hyun-Kee Min, In-Hak Lee, In-Ho Jeong, Byung-Tak Jang, and Choong-Mo Nam
Department of Electronics Engineering, Korea Polytechnic University |
| TB2-H-2 | 13:25-13:40 | Analysis of Instability Mechanism under simultaneous positive Gate and Drain Bias Stress in Self-Aligned Top-Gate Amorphous Indium-Zinc-Oxide Thin-Film Transistors
Jonghwa Kim, Sungju Choi, Jaeman Jang, Jun Tae Jang, Jungmok Kim, Sung-Jin Choi, Dong Myong Kim, and Dae Hwan Kim
School of Electrical Engineering, Kookmin University |
| TB2-H-3 | 13:40-13:55 | A New ISP Function to Support Gain Control at Each Input Code
Younghwan Yun
Application Engineering Team, SK Hynix Inc. |
| TB2-H-4 | 13:55-14:10 | Low-Temperature All-Solution-Processed Indium Oxide Thin-Film Transistors
Seon-Beom Ji, Narkhyeon Seong, Jewook Ha, and Yongtaek Hong
Department of Electrical Engineering and Computer Science, Inter-University Semiconductor Research Center (ISRC), Seoul National University |
| TB2-H-5 | 14:10-14:25 | Comparative Analysis on Positive Bias Stress-Induced Instability under HVGS and HVDS in Amorphous InGaZnO Thin-Film Transistors
Hara Kang, Jun Tae Jang, Jonghwa Kim, Sung-Jin Choi, Dong Myong Kim, and Dae Hwan Kim
School of Electrical Engineering, Kookmin University |